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**Contactless Terahertz Sensing of Ultrafast Switching in Marx Generator Based on Avalanche Transistors**

*Published in:* IEEE Electron Device Letters

**DOI:**
[10.1109/LED.2022.3199996](https://doi.org/10.1109/LED.2022.3199996)

Accepted/In press: 01/01/2022

Please cite the original version:
Abstract—In this paper, we have studied the temporal evolution of switching for each stage of the Marx generator with picosecond temporal and millimeter spatial resolutions employing terahertz measurements. The Marx circuit utilizes collapsing-field-domain (CFD)-based avalanche switches, which are formed in a bipolar GaAs structure and result in the picosecond speed of powerful carrier generation and electrical switching. The application of the CFD-based avalanche switches emitting mm-wave pulsed radiation in the Marx generator provides a unique opportunity to accurately track the switching instants for each of the circuit stages with a picosecond time precision. The collapsing domains cause the sub-THz pulses radiated by each of the avalanche switches, and the same domains generate the electron-hole plasma thus causing simultaneously the electrical switching. In this work, we report the direct measurements of the switching instants for each of the four stages Marx generator and suggest an interpretation of non-trivial experimental results.

Index Terms—Marx generators, avalanche breakdown, solid-state terahertz (THz) pulsed source.

I. INTRODUCTION

Marx circuits are typically used to generate high-voltage pulses [1], but can also be used to significantly increase the peak current across a load [2] and include a broad variety of applications [3]–[5]. They utilize solid-state switches [6] where the switching mechanism is triggered by a voltage, exceeding the threshold, applied between the anode and cathode, or, alternatively, by the dV/dt effect, when the turn-on is initiated by a sharp voltage ramp. The same physics also works in avalanche transistors [2].

One hypothesis regarding the operation of the Marx generator is that switching happens simultaneously in all stages. However, this claim is difficult to experimentally verify, at least for high-speed ns- and sub-ns switching times, since high-speed oscilloscope probing of individual switching events is complicated by spatially and temporally varying potentials on the ground plane. Alternatively, free space microwave pulsed emission can be used for the switching instants detection but it is very challenging to attribute the pulses to a particular transistor: the characteristic wavelengths of emitted ultrawideband microwave pulses (≈ few dm) typically exceed the size of the entire circuit board, further confounding source localization.

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Manuscript received XX.XX.XXX; revised XX.XX.XXX.

II. EXPERIMENTAL SETUP AND DEVICE UNDER TEST

Fig. 1 shows a diagram of a pulsed 200 GHz source consisting of mm-size on-chip bow-tie antenna (Aₜ) (a) and CFD-avalanching, GaAs transistor (b) [7]. The equivalent circuit of the Marx generator and its printed circuit board (PCB) view are shown in Fig. 1 (c) and (d), respectively. The on-chip antenna can be approximated as an RLC-circuit shown in the insert (e) of the same figure with the following parameters: Cₐ = 85 fF, Lₐ = 8 pH and Rₐ = 35 Ω. This low-inductance (Lₐ) antenna circuit interacts with CFDs in the avalanche switch thus affecting sub-THz oscillations and the emission, but does not affect the avalanche switching itself due to the small Cₐ. Capacitors (C) and inductors (L) form the circuit loop which operates in a sub-ns avalanche switching regime (1–10 GHz band), while 200 GHz oscillations caused by CFDs cannot penetrate this large inductance (L_total > 4L) circuit. Unlike the devices with base-triggering described in Ref. [7], the avalanche switching in the current device is initiated by the avalanche breakdown of the base-collector junction at V₀ ≈ 22 V.

Terahertz sensing can shed additional light on this problem. Ultra-high amplitude, ultra-narrow collapsing field domains (CFDs) in the collector of a GaAs avalanche transistor [7], are caused by negative differential mobility at extreme fields [8] and lead to ultrafast electrical switching [9] due to powerful ionization. Concomitant sub-THz current oscillations across the conductive channels [10] result in electromagnetic waves emission when the current is coupled to an on-chip antenna. These features enable embedding ultrafast picosecond-range GaAs avalanche transistors in a Marx-bank high-voltage pulse generator circuit [11] and analyzing the sub-THz pulses radiated by each transistor.

In this letter, we investigate a four-stage CFD-based Marx generator and demonstrate a contactless sensing method for ultrafast switching analysis in each stage by means of quasioptical terahertz direct detection. CFDs associated with the avalanche switching produce millimeter-wave emissions corresponding to 200 GHz. The free space wavelengths are similar in size to the antenna coupled to the avalanche transistor, and consequently, the switching instants of different transistors can be easily separated by spatially isolating each emission. Since CFD-based switches can be incorporated into other solid-state devices and circuits, the methodology may have applications in modern optoelectronics metrology and allow fully contactless and nondestructive sensing and characterization of switching in avalanche semiconductor devices by quasioptic means.
in a series connection of all capacitors $C$ discussed above. Then, even higher voltage ramps trigger voltage across $S_1$ of capacitor $C$, which is provided in Ref. [3], [12], [13]. The biasing voltage of more complicated Marx generators and their characteristics oscillations. The more detailed studies of impedance matching current amplitude, and gives as narrow the current pulse as resistor ($R_{\text{ELtesta}}$), which is triggered by the pulse across the load $0$ is then amplified ($R_1$) recorded at the second input. We have selected an optimized $R_{\text{load}}$ which is about equal to the output impedance of the entire circuit, provides relatively high current amplitude, and gives as narrow the current pulse as possible but prevents, however, an appearance of relaxation oscillations. The more detailed studies of impedance matching in more complicated Marx generators and their characteristics are provided in Ref. [3], [12], [13]. The biasing voltage of $V_g = 23 \text{ V}$ is sufficient for periodic self-triggering of the Marx circuit without an external generator with a repetition rate of $1.5 - 2 \text{ MHz}$ determined by the bias voltage and $(R_1 + R_2) \times C$ product.

### III. Results and Discussion

Transistor $S_1$ (Fig. 1) has a breakdown voltage $V_{b^1_{S_1}} \approx 21.9 \text{ V}$, while others $V_{b^2\ldots_{S_4}} \approx 22 \text{ V}$. Initial charging of the capacitor $C$ in the first stage within $t \approx 0.5 \mu \text{s}$ increases the voltage across $S_1$ to the breakdown value, leading to switching of $S_1$, and then a negative voltage ramp is applied to the emitter of $S_2$, triggers its switching defined by mechanisms discussed above. Then, even higher voltage ramps trigger emitters $S_3$ and $S_4$. Switching of all four stages results in a series connection of all capacitors $C$, and the voltage

$$\sum_{i=1}^{4} V_{S_i} - \text{residual voltages across } S_{1-4} \text{ is detected at the load resistor } R_{\text{load}}. \text{ The current pulse across the load is shown in Fig. 3, after numerical reduction of parasitic inductance [7].}

The oscillatory behavior of the current pulse rising edge in Fig. 3 is associated with corresponding instants of the transistors $S_{1-4}$ switching. We attribute the peak in the rising sub-THz pulse intensity emitted by a particular transistor to the moment when the ionization in CFDs results in a significant increase of electron-hole plasma density in the conductive channel, and the voltage across the transistor starts reducing due to the CFDs shrinkage [9], [14]. Then the voltage across other transistors and the load grows, resulting in the rise of the current. For example, the ionization peak in transistor $S_1$ can be attributed to the instant at $t = 120 \text{ ps}$ (with a voltage at the Schottky detector $V_{S_1}(120 \text{ ps}) = 0.73 \text{ V}$), and the corresponding increase in the current limited by the inductance lasts $t = 180 \text{ ps}$. Further boost of the current between $200 \text{ ps}$ and $292 \text{ ps}$ is related to the combined effect of $S_2$ and $S_3$ switching, whereas the final current rise between $350 \text{ ps}$ and $425 \text{ ps}$ is caused by the switching of transistor $S_4$. The significant delays in switching processes between the stages,
ranging between 60 ps and 70 ps, are comparable with the switching time of each transistor. Finally, we attribute the abrupt break in radiation from switches \( S_{2-4} \) at \( t = 500 \text{ ps} \) (Fig. 3) to the domains collapse at an extremely high carrier density [8], [9], [14]. Well pronounced differences in the amplitude of the radiation from \( S_1 \) and other transistors (\( S_{2-4} \)) are enumerated below.

The interpretation of inter-cascade switching delays relies on the earlier findings [9], [10], [14] related to the CFD phenomenon. The first avalanche switching phase caused by the electron injection from the emitter and hole avalanche injection from the subcollector occurs when the current density exceeds the critical value of 30 kA/cm\(^2\) (for the transistors with the collector doping of 2 \( \times 10^{16} \) cm\(^{-2}\) used here), and the entire emitter-base perimeter participates in the switching (with the conducting area of \( \approx 10 \mu \text{m}^2 \)). Thus, a relatively slow (up to 1 ns) transient of the first switching phase occurs when the current across the transistor exceeds 3 mA.

The second, ultrafast switching phase, accompanied by the CFD formation and filamentation, starts when the current density exceeds \( \approx 300 \text{ kA/cm}^2 \) across the filament with an area of 2 \( \mu \text{m}^2 \), which requires the total current of at least 6 mA across the transistor. When \( V_{bd} \) is reached, the resistance \( R_1 \) is large, and the current for the first avalanche switching phase is supplied only by the capacitors chain \( C_L \), load resistor \( R_{load} \), and switched-off (so far) transistors \( S_{2-4} \). The displacement current across the barrier capacitances of \( S_{2-4} \) is \( C_L \approx 1.5 \text{ fF} \) for each transistor and \( 0.5 \text{ fF} \) for the series connection of three transistors \( S_{2-4} \) provides a current of 3 mA across the switch \( S_1 \), which supports the first switching phase in \( S_1 \), but cannot provide the current level for the second switching phase.

The further switching scenario of the Marx circuit is as follows. “Slow” reduction in the voltage across \( S_1 \) within the first phase redistributes the voltage across the chain \( S_{1-4} \) which causes the avalanche process initiation in the switches \( S_2, S_3 \), and \( S_4 \). After the delay, slowly switching transistors \( S_{2-4} \) provide a current of more than 6 mA across \( S_1 \) sufficient for ultrafast filamentary switching. Fast reduction in the voltage across \( S_1 \) increases the voltage across the transistors \( S_{2-4} \) still further, and then transistor \( S_2 \) reaches the threshold of filamentary CFD-assisted switching. The same process is repeated then for \( S_3 \) and later for \( S_4 \).

Thus, we attribute the inter-stage switching delays to the time intervals required for the interphase changeover in each transistor. Namely, \( S_1 \) realizes CFD-based filamentary switching with a limited current supply across \( S_{2-4} \), while \( S_2 \) starts the ultrafast switching when the voltage across \( S_3 \) and \( S_4 \) exceeds the breakdown level significantly, and the current supplied by \( S_2 \) is remarkably larger. The more it concerns the ultrafast switching process of \( S_3 \) and \( S_4 \). All in all, the ultrafast switching of \( S_1 \), which happens at the strongest external current limitation, should form the area of the switching filament as small as possible for the CFDs formation. This should result in domains with limited amplitude, and minimal conductivity in the channels during the entire current pulse. These features can explain the reduced radiation amplitude due to limited current oscillations in the antenna \( A_1 \), as demonstrated in Fig. 3. Furthermore, the radiation recorded from \( S_1 \) lasts longer than that from other transistors. We think that the electron-hole plasma density in the switching filament of the first transistor is lower (due to current limitation when the filament has been formed), and that is why the CFD collapse caused by access plasma density occurs in \( S_{2-4} \) earlier than in \( S_1 \).

Perfect switching synchronization of all stages utilizing ultrafast components likely requires a certain “smart” Marx circuit design, in which all the switches pass the first switching stage simultaneously and with identical conditions. In this case, the “voltage wave” running along the circuit stages would cause an ultrafast filamentary switching realized synchronously for all the transistors.

Additional verification of our findings has been performed with a similar circuit, in which triggering started not from \( S_1 \), but from \( S_4 \). The result is nearly identical, with similar interstage delays, but with the reverse switching order. Thus, the circuit can be implemented with an inverted switching process, but instead of negative voltage ramps applied to the emitters, it uses negative voltage ramps applied to collectors.

### IV. Conclusion

In summary, a four-stage Marx generator circuit utilizing picosecond-range switches with simultaneous sub-THz emission has been investigated. Namely, a contactless method for terahertz sensing of ultrafast switching in Marx generator based on avalanche transistors has been proposed. A unique combination of picosecond temporal and millimeter spatial resolution has allowed the timing synchronization between the stages to be directly measured.

We have particularly observed that the current pulse generated by the Marx circuit can be approximately five times longer than the shortest sub-THz pulse (\( \tau \approx 100 \text{ ps} \) emitted by the last-switched transistor \( S_4 \)). The significant increase in the current pulse duration across the load resistor is attributed to the following factors: the inter-stage switching delays, and the different duration of the domain regime in each transistor. The last one is affected by the time-dependent impedance of the entire circuit. Namely, transistor \( S_4 \) reaches its CFD switching mode when other transistors have already been switched. Thus, the circuit impedance does not strictly limit the current supplied by the external circuit, and the CFD carrier generation runs most efficiently that takes the shortest time. On the contrary, transistor \( S_1 \) switches at the highest impedance of the entire circuit, which reduces the efficiency of the CFD switching process, and the transient takes a longer time.

The discovered results suggest an idea for optimized temporal synchronization of picosecond components combined in the Marx circuit.

### Acknowledgements

The authors also would like to thank Dr. V. Zemlyakov and Prof. I. Prudayev for fruitful discussions and comments. Prof. V. Mikhnev is acknowledged for providing the antenna parameters.
REFERENCES


